

# AOSP66925

## 100V N-Channel AlphaSGT™

## **General Description**

- Trench Power AlphaSGT<sup>™</sup> technology 100V
- Low R<sub>DS(ON)</sub>
- Logic Level Driving
- Excellent Q<sub>G</sub> x R<sub>DS(ON)</sub> Product (FOM)
- RoHS 2.0 and Halogen-Free Compliant

## **Applications**

• High Frequency Switching and Synohronous Rectification.

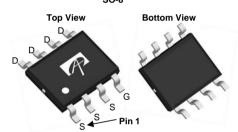
## **Product Summary**

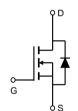
 $\begin{array}{lll} V_{DS} & 100V \\ I_{D} \; (at \, V_{GS} \! = \! 10V) & 11A \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 10V) & < 12.5 m\Omega \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 4.5V) & < 16.8 m\Omega \end{array}$ 

100% UIS Tested 100% Rg Tested



SO-8





Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOSP66925	SO-8	Tape & Reel	3000

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		$V_{DS}$	100	V	
Gate-Source Voltage		$V_{GS}$	±20	V	
Continuous Drain	T <sub>A</sub> =25°C		11		
Current	T <sub>A</sub> =70°C	'D	8.6	А	
Pulsed Drain Current <sup>c</sup>		I <sub>DM</sub>	44		
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	32	А	
Avalanche energy	L=0.1mH <sup>C</sup>	E <sub>AS</sub>	51	mJ	
	T <sub>A</sub> =25°C	В	3.1	W	
Power Dissipation <sup>B</sup>	T <sub>A</sub> =70°C	P <sub>D</sub>	2	v	
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C	

Thermal Characteristics					
Parameter		Symbol	Тур	Max	Units
Maximum Junction-to-Ambient A	t ≤ 10s	P	31	40	°C/W
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	59	75	°C/W
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	16	24	°C/W



#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
STATIC PARAMETERS							
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V	
	Zero Gate Voltage Drain Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			1	μA	
DSS	Zero Gate Voltage Drain Gurrent	T <sub>J</sub> =55°C			5	μΛ	
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V			±100	nA	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.6	2.1	2.6	V	
R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =10V, I <sub>D</sub> =11A		10.4	12.5	mΩ	
	T <sub>J</sub> =125°C		18.8	22.6	11152		
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =11A		13.4	16.8	mΩ	
g <sub>FS</sub>	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=11A$		41		S	
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.7	1	V	
Is	Maximum Body-Diode Continuous Curre	ent			4	Α	
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance			1590		pF	
Coss	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =50V, f=1MHz		390		pF	
C <sub>rss</sub>	Reverse Transfer Capacitance			8		pF	
$R_g$	Gate resistance	f=1MHz	0.45	0.9	1.35	Ω	
SWITCHI	NG PARAMETERS						
$Q_g(10V)$	Total Gate Charge			23	33	nC	
$Q_g(4.5V)$	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =50V, I <sub>D</sub> =11A		11	16	nC	
$Q_{gs}$	Gate Source Charge	J VGS=10V, VDS=00V, ID=117V		4.7		nC	
$Q_{gd}$	Gate Drain Charge			3.5		nC	
Q <sub>oss</sub>	Output Charge	$V_{GS}$ =0V, $V_{DS}$ =50V		32		nC	
t <sub>D(on)</sub>	Turn-On DelayTime			8		ns	
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =50V, $R_L$ =4.5 $\Omega$ ,		3		ns	
$t_{D(off)}$	Turn-Off DelayTime	$R_{GEN}=3\Omega$		26		ns	
t <sub>f</sub>	Turn-Off Fall Time			5		ns	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =11A, di/dt=500A/μs		130		ns	
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =11A, di/dt=500A/μs		28		nC	

A. The value of R<sub>BJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ$  C, using  $\leq$  10s junction-to-ambient thermal resistance. C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ$  C. Ratings are based on low frequency and duty cycles to keep initialT<sub>J</sub>=25° C.

D. The  $R_{\theta,JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta,JL}$  and lead to ambient.

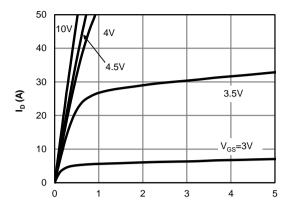
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in? FR-4 board with

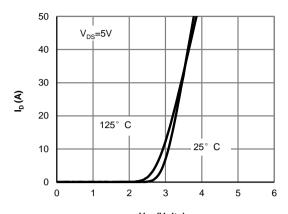
<sup>2</sup>oz. Copper, assuming a maximum junction temperature of  $T_{J(MAX)}$ =150° C. The SOA curve provides a single pulse rating.



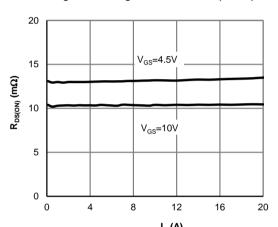
#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



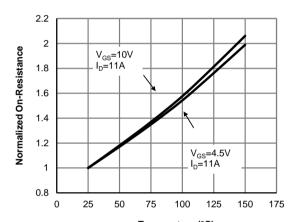
 $V_{\rm DS}$  (Volts) Figure 1: On-Region Characteristics (Note E)



V<sub>GS</sub> (Volts) Figure 2: Transfer Characteristics (Note E)



 $\label{eq:local_potential} \mathbf{I_{D}}\left(\mathbf{A}\right)$  Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)

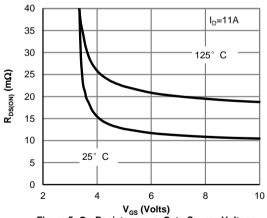
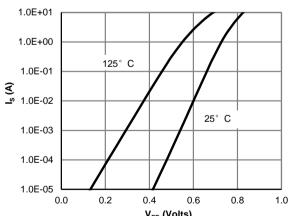


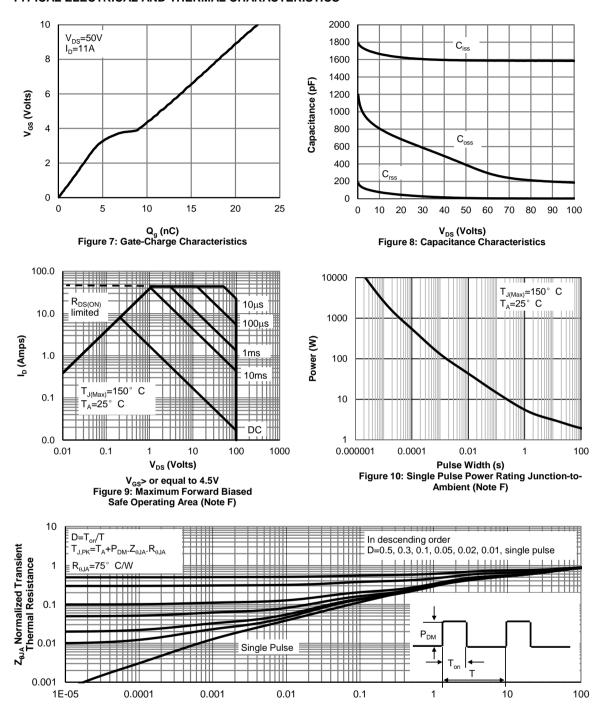
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Figure A: Gate Charge Test Circuit & Waveforms

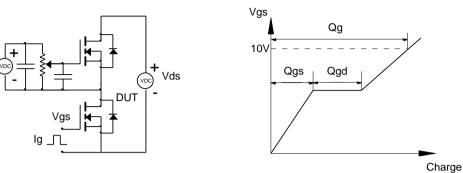


Figure B: Resistive Switching Test Circuit & Waveforms

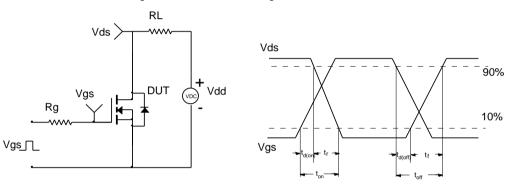


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

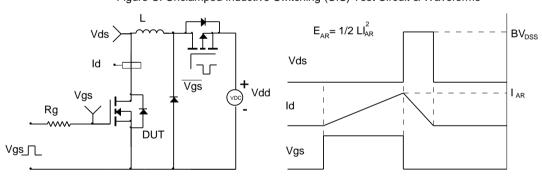
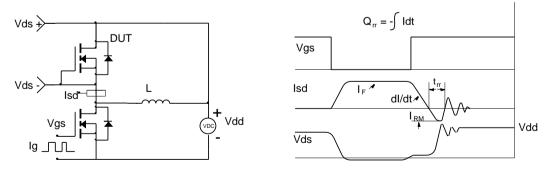


Figure D: Diode Recovery Test Circuit & Waveforms



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